

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/626,693	MEYER, JOHN F.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,283,820 A	02-1994	Ishiwatari et al.	379/100.02
*	B	US-5,900,947 A	05-1999	Kenmochi et al.	358/442
*	C	US-6,111,662 A	08-2000	Satoh et al.	358/442
*	D	US-6,166,826 A	12-2000	Yokoyama, Shoji	358/1.16
*	E	US-6,295,391 B1	09-2001	Rudd et al.	382/313
*	F	US-2001/0019416 A1	09-2001	Monty et al.	358/1.9
*	G	US-6,337,712 B1	01-2002	Shiota et al.	348/231.1
*	H	US-6,552,743 B1	04-2003	Rissman, Paul	348/207.2
*	I	US-6,765,686 B2	07-2004	Maruoka, Hiroshi	358/1.15
*	J	US-6,832,083 B1	12-2004	Oba et al.	455/412.1
*	K	US-6,867,879 B1	03-2005	Sasaki et al.	358/1.18
*	L	US-6,943,906 B2	09-2005	Murata, Kazuyuki	358/1.13
*	M	US-7,019,869 B2	03-2006	Chen, Michael	358/402

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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NON-PATENT DOCUMENTS

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	U	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,926,325 A	05-1990	Benton et al.	705/39
*	B	US-5,282,054 A	01-1994	Oana et al.	358/406
*	C	US-5,487,106 A	01-1996	Kenmochi et al.	379/100.02
*	D	US-5,548,417 A	08-1996	Sekimoto et al.	358/474
*	E	US-5,668,570 A	09-1997	Ditzik, Richard J.	345/173
*	F	US-D390,225 S	02-1998	Bowden, Stephen Gray	D14/146
*	G	US-5,760,917 A	06-1998	Sheridan, Keith Holden	358/442
*	H	US-6,115,137 A	09-2000	Ozawa et al.	358/1.6
*	I	US-2001/0020977 A1	09-2001	Watanabe, Yoshikazu	348/222
*	J	US-6,283,646 B1	09-2001	Dellert et al.	396/564
*	K	US-6,426,801 B1	07-2002	Reed, William Henry	358/1.16
*	L	US-2003/0080949 A1	05-2003	Ditzik, Richard J.	345/173
*	M	US-6,657,702 B1	12-2003	Chui et al.	355/40

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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		Madeleine AV Nguyen	2625	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,959,871 A	09-1990	Mori et al.	382/313
*	B	US-5,250,986 A	10-1993	Axten et al.	341/23
*	C	US-5,436,730 A	07-1995	Hube, Randall R.	358/401
*	D	US-5,528,375 A	06-1996	Wegeng et al.	358/296
*	E	US-6,023,727 A	02-2000	Barrett et al.	709/221
*	F	US-6,785,366 B1	08-2004	Nobuta et al.	379/88.03
*	G	US-6,876,737 B1	04-2005	Allani et al.	379/220.01
*	H	US-7,142,846 B1	11-2006	Henderson, Daniel A.	455/417
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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